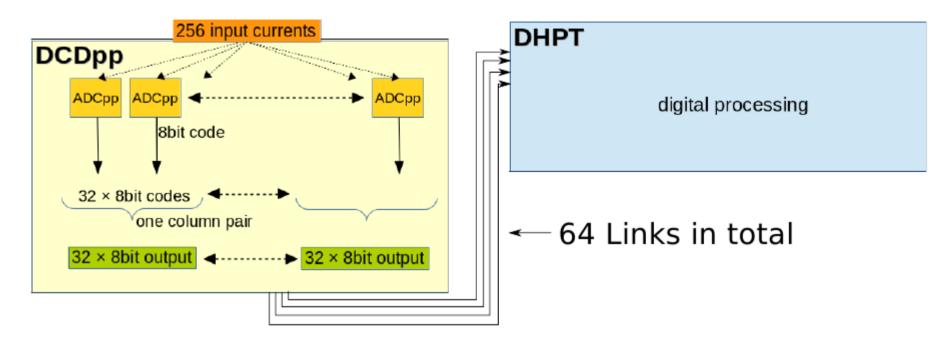


DCD4.1/DCD4.2 Review Digital Performance

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- 64 Links connect the DCD to the DHPT (8 x 8-Bit Link)
- For each link a local delay can be set to ensure a proper timing
- In addition to the local delays, a global delay can be set
- These delays have to be optimized



- Communication between DCD and DHP is tested by using a special test pattern
- DCD4.2 uses a new, more complicated test pattern
- DCD4.X feature a LVDS current boost to improve the communication



DCD Test Pattern Comparison

Test pattern is used to check the correct communication between DCD and DHP and choose the correct delay settings

• DCD4.1

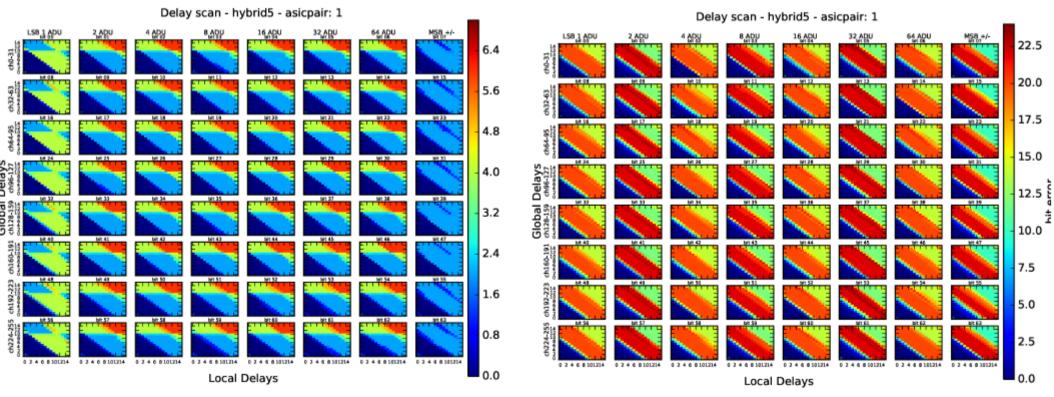
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- DCD4.2
 - new, complex test pattern

LVDS current boost

old, simple test pattern

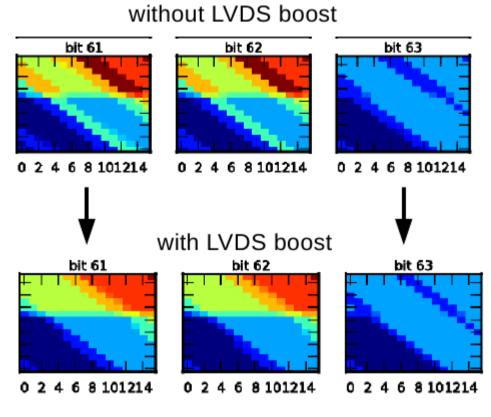


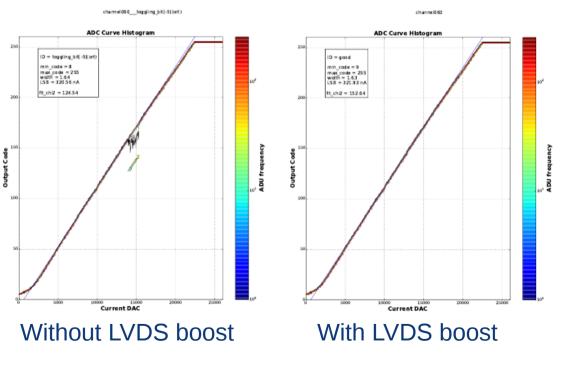




- Increase LVDS current from 1.3 to 1.8 mA
- Observation:

- Communication is stabilized
- "good" region is broadened

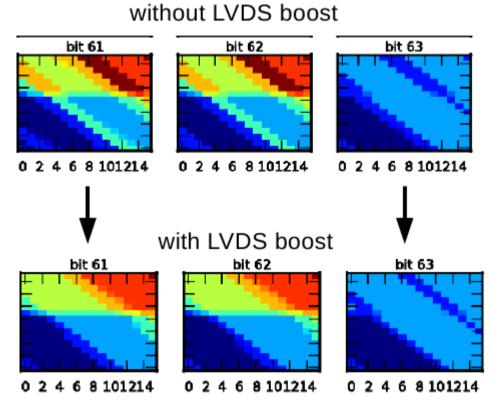


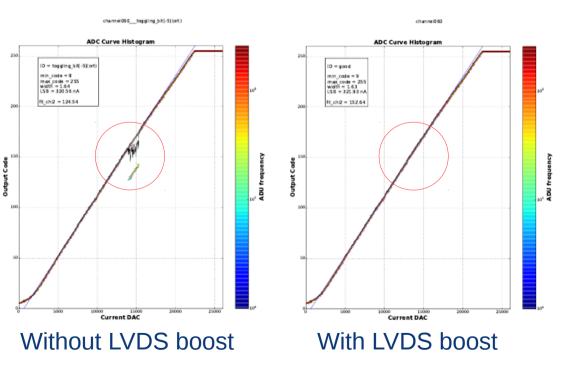




- Increase LVDS current from 1.3 to 1.8 mA
- Observation:

- Communication is stabilized
- "good" region is broadened







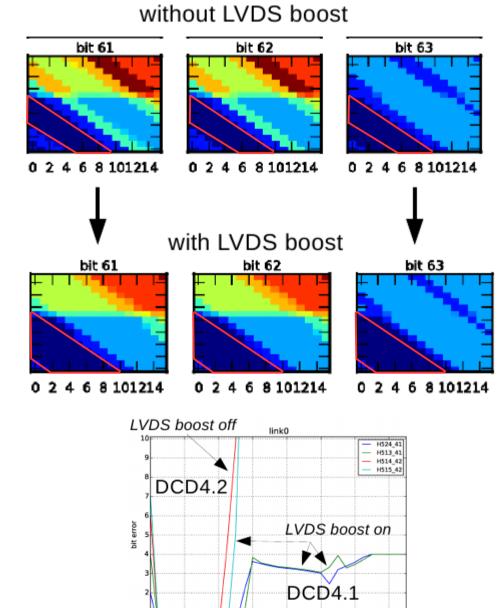
- Increase LVDS current from 1.3 to 1.8 mA
- Observation:

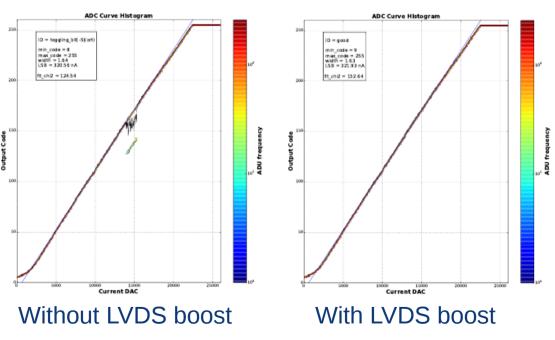
channel060__toggling_bit[-5](ort)

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- Communication is stabilized
- "good" region is broadened

channel060





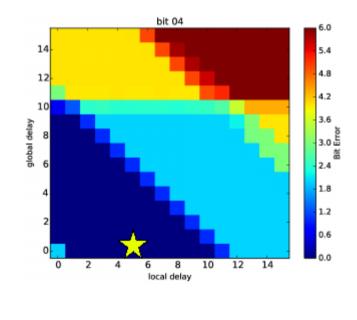
24

16



Module	Global delay	Local delay range
H5.0.24 (DCD4.1)	0	[4,6]
H5.0.13 (DCD4.1)	0	[4,6]
H5.0.14 (DCD4.2)	0	[2,4]
H5.0.15 (DCD4.2)	1	[3,4]

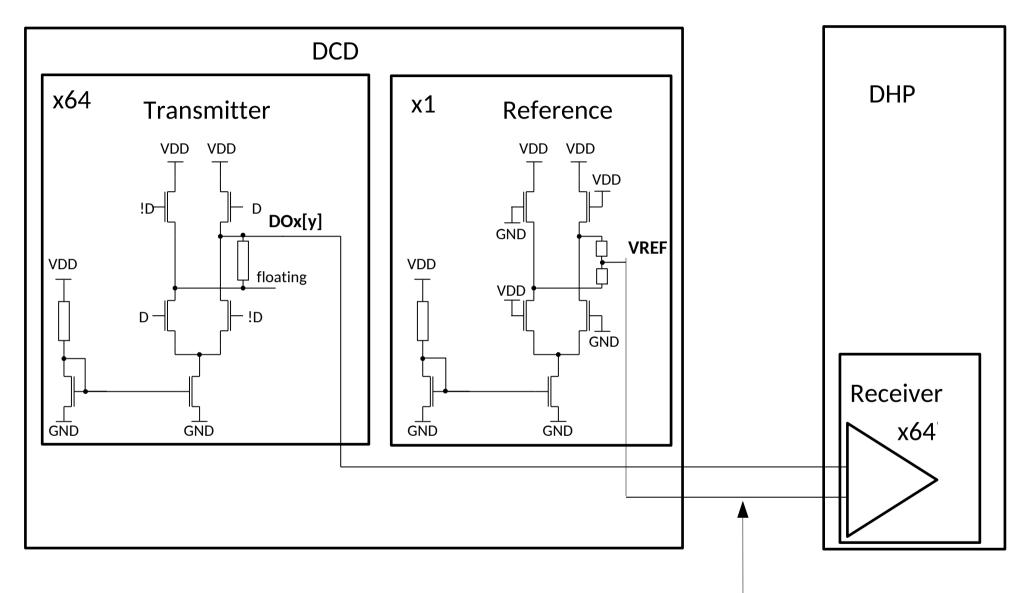
- Data link delays for all DCD4.1 and DCD4.2 were successfully optimized, delay values are similar
- Both test pattern can be used for the optimization
- LVDS boost improves communication







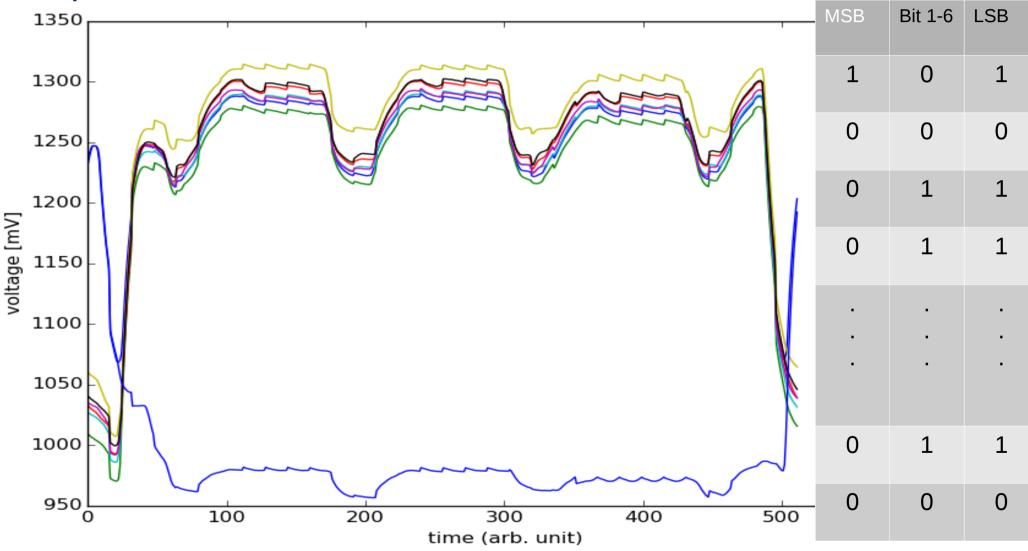
DCD Waveform



Reference Voltage can be changed from the outside

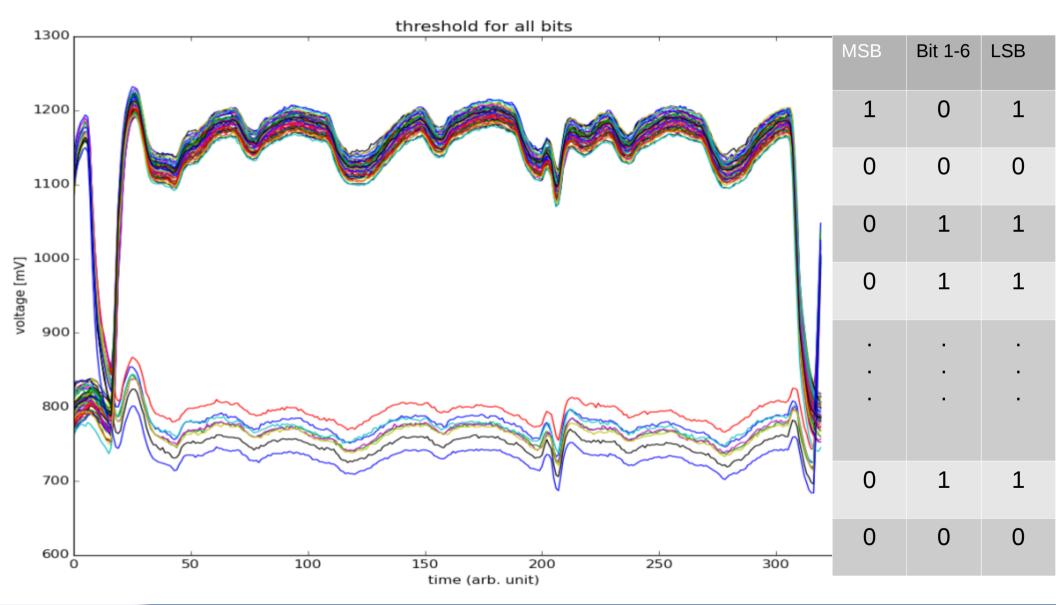


All bits of one link at 1.9V VDDD **DCDpp 3**, 250MHz, test pattern enabled



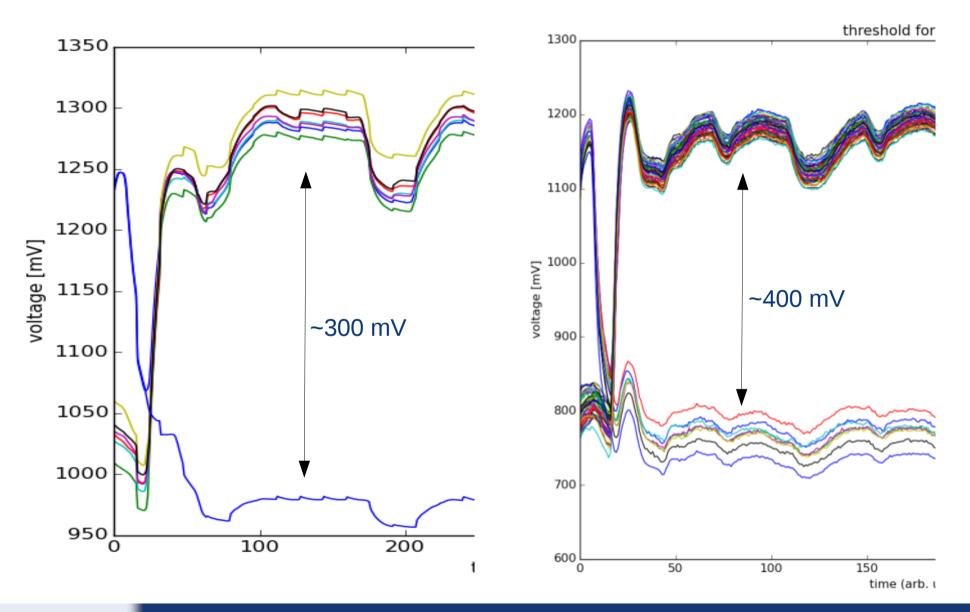


All bits of all links at 1.9V DVDD DCDB4.1, boost on, 305MHz



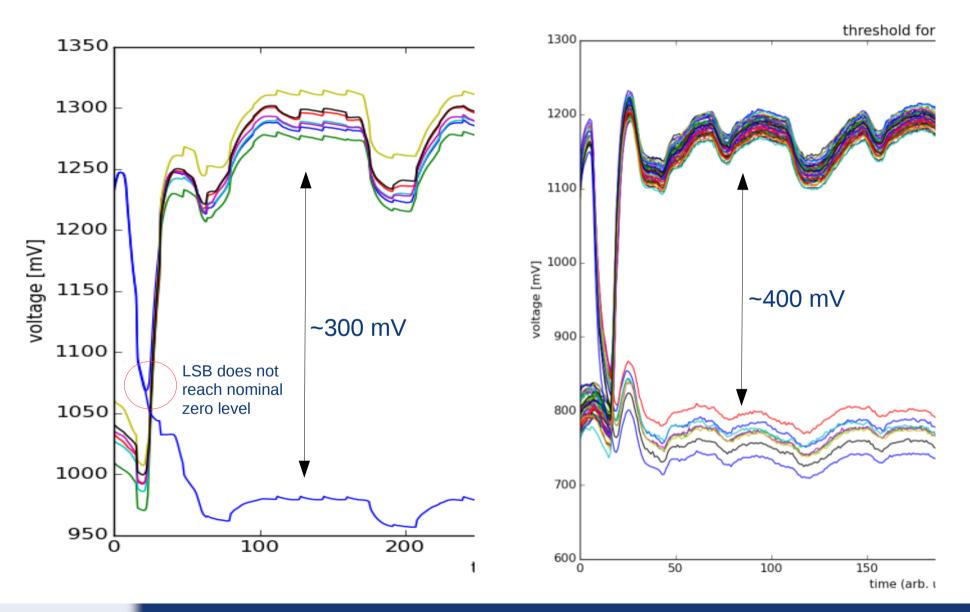


Comparison of DCDpp and DCDB4.1



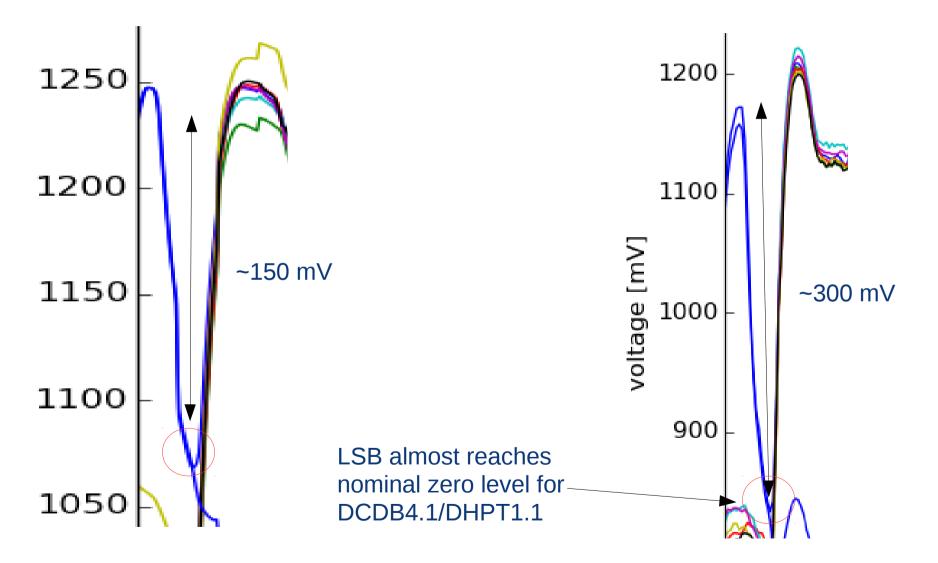


Comparison of **DCDpp** and **DCDB4.1**





Comparison of **DCDpp** and **DCDB4.1**



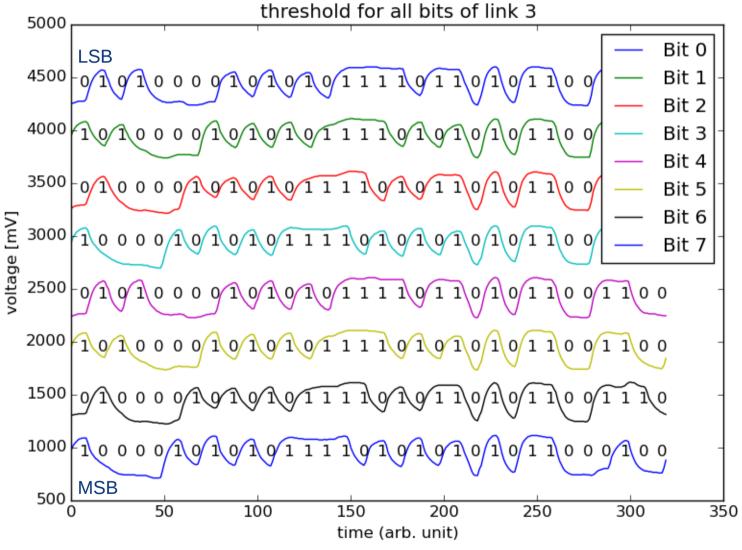
DCD Waveform

new test pattern



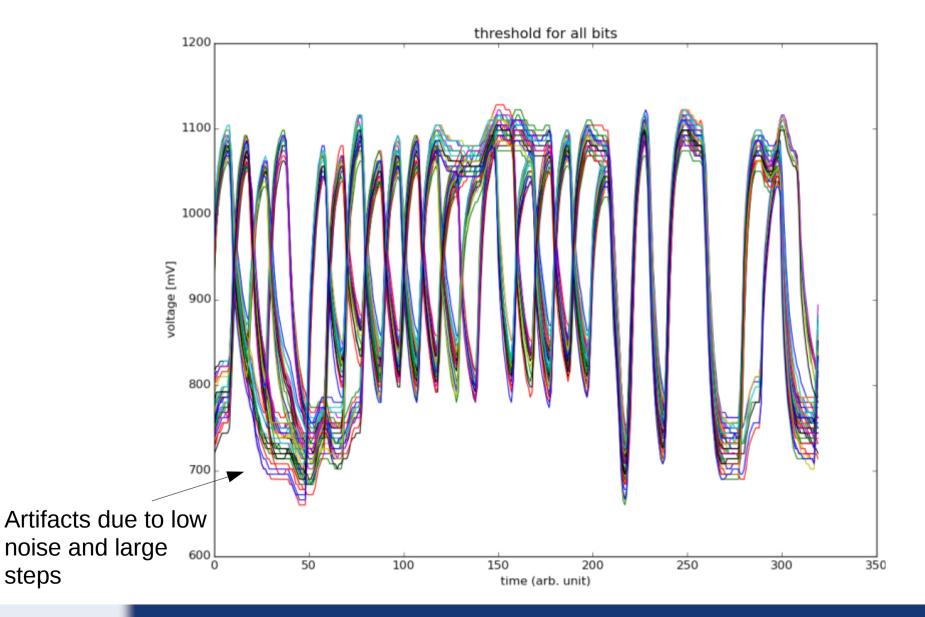
DCDB4.2 lines stacked

Index MSB LSB Value 0 1 0 0 0 0 0 0 0 -86 -120 -86 -86 -86 -35 -18 -1 0 1 Index MSB LSB Value -69 -86 -86





All bits of all links at 1.8V DVDD DCDB4.2, boost on, 305MHz

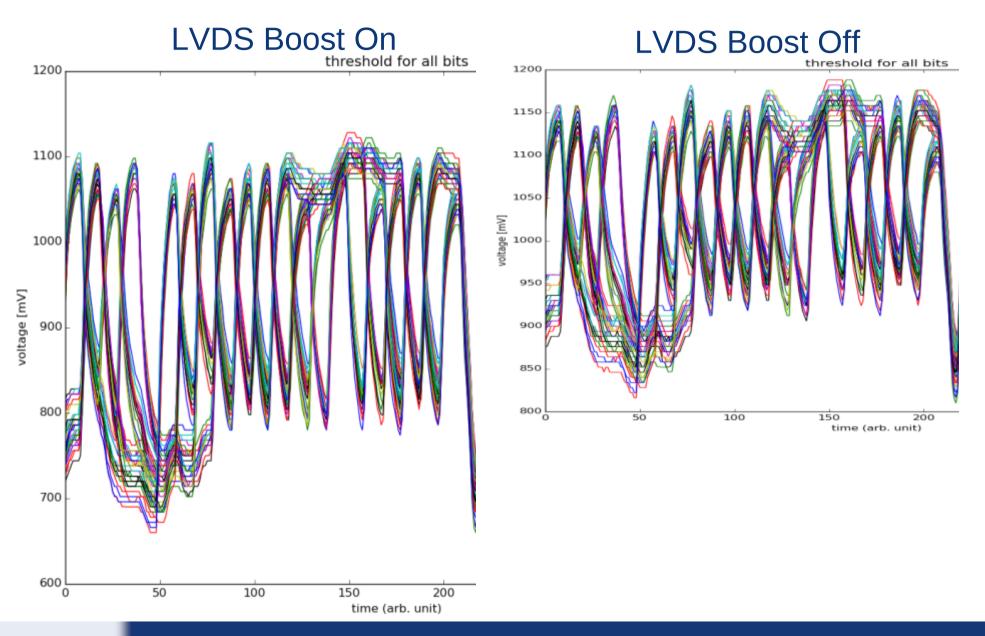


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DCD Waveform

All bits of all links at 1.8V DVDD DCDB4.2, 305MHz

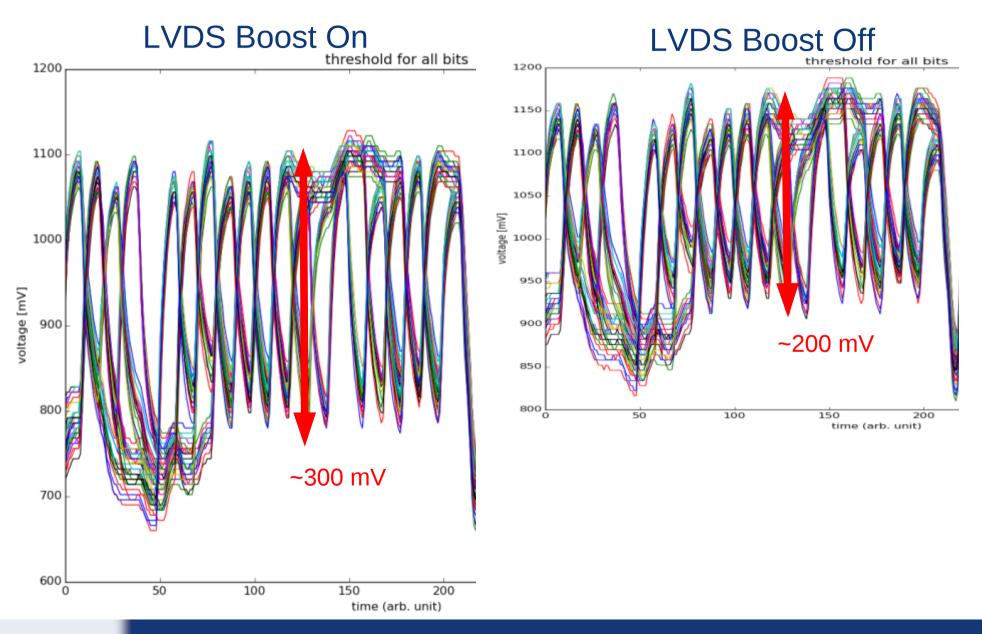


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ASIC Communication

All bits of all links at 1.8V DVDD DCDB4.2, 305MHz





- Both test pattern can be used to optimize the global/local delay settings
- The new LVDS boost implemented in DCD4.X helps to suppress bit errors and stabilize the communication
- The waveform is improved in comparison to the DCDpp
- Communication is significantly improved with DCD4.X